

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Shane C. Hu et al.	Examiner:	Mehdi Namazi
Serial No.:	09/901,811	Group Art Unit:	2189
Filed:	July 10, 2001	Docket:	303.739US1
Title:	CACHING OF DYNAMIC ARRAYS		

INFORMATION DISCLOSURE STATEMENT

MS RCE
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement. However, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Information Disclosure Statement considered.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

Respectfully submitted,

SHANE C. HU ET AL.

By their Representatives,

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Date 5-2-06

By M L B
Marvin L. Beekman
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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being filed using the USPTO's electronic filing system EFS-Web, and is addressed to: Mail Stop RCE, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 2 day of May, 2006.

Karen Gannon
Name

Karen G
Signature

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Use as many sheets as necessary)</i>		<i>Complete if Known</i>	
		Application Number	09/901,811
		Filing Date	July 10, 2001
		First Named Inventor	Hu, Shane
		Group Art Unit	2189
		Examiner Name	Namazi, Mehdi
Sheet 1 of 1		Attorney Docket No: 303.739US1	

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-5,526,506	06/11/1996	Hyatt, Gilbert P.	09/04/1990
	US-5,898,858	04/27/1999	Gillespie, B.	09/28/1995

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		KANDEMIR, M., et al., "Improving Memory Energy Using Access Pattern Classification", <u>Proceedings, IEEE/ACM International Conference on Computer Aided Design</u> , (November 4-8, 2001), 201-206	
		PARK, J. W., "An Efficient Buffer Memory System for Subarray Access", <u>IEEE Transactions on Parallel and Distributed Systems</u> , 12(3), (Mar., 2001), 316-335	
		SHETH, V. R., et al., "Real Time Failure Analysis of Cu Interconnect Defectivity Through Bitmap Overlay Analysis", <u>IEEE/SEMI Advanced Semiconductor Manufacturing Conference</u> , (September 8-10, 1999), 8-13	

EXAMINER
DATE CONSIDERED